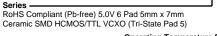


$\underbrace{\text{EV31C3}}_{\text{n}} \begin{array}{c} \mathbf{A} \\ \end{array} \begin{array}{c} \mathbf{5} \\ \mathbf{A} \end{array} \begin{array}{c} \mathbf{5} \\ \mathbf{A} \end{array} \begin{array}{c} \mathbf{A} \\ \mathbf{T} \end{array} \begin{array}{c} \mathbf{1} \\ \mathbf{T} \end{array} \begin{array}{c} -27.000 \text{M} \\ \hline \end{array} \begin{array}{c} \text{TR} \\ \hline \\ \text{Packaging Options} \\ \text{Tape \& Reel} \end{array}$



Operating Temperature Range 0°C to +70°C

Absolute Pull Range

±100ppm Minimum

Linearity _____ 10% Typical, 20% Maximum Nominal Frequency 27.000MHz

- Duty Cycle 50 ±5(%) Typical, 50 ±10(%) Maximum

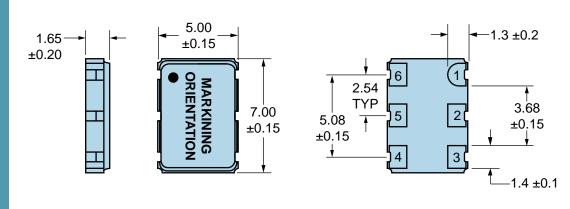
ELECTRICAL SPECIFICATIONS

Nominal Frequency	27.000MHz
Frequency Tolerance/Stability	±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, Shock, and Vibration.)
Aging at 40°C	±2ppm/First year typical, ±10ppm/10 Years Maximum
Operating Temperature Range	0°C to +70°C
Supply Voltage	5.0Vdc ±10%
Input Current	25mA Maximum
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH = -4mA)
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL = +4mA)
Rise/Fall Time	5nSec Maximum (Measured at 0.4Vdc to 2.4Vdc with TTL Load; Measured at 20% to 80% of waveform with HCMOS Load)
Duty Cycle	50 \pm 5(%) Typical, 50 \pm 10(%) Maximum (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load)
Load Drive Capability	10TTL Load or 30pF HCMOS Load Maximum
Output Logic Type	CMOS
Absolute Pull Range	±100ppm Minimum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, Shock, Vibration, and Aging over the Control Voltage (Vc).)
Control Voltage	0.5Vdc to 4.5Vdc (Test condition for Absolute Pull Range)
Control Voltage Range	0.0Vdc to Vdd
Linearity	10% Typical, 20% Maximum
Transfer Function	Positive Transfer Characteristic
Modulation Bandwidth	10kHz Minimum (Measured at -3dB, Vc = 2.5Vdc)
Input Impedance	50kOhms Minimum
Input Leakage Current	10µA Maximum
Phase Noise	-70dBc/Hz at offset of 10Hz, -100dBc/Hz at offset of 100Hz, -130dBc/Hz at offset of 1kHz, -147dBc/Hz at offset of 10kHz, -152dBc/Hz at offset of 100kHz, and -155dBc/Hz at offset of 1MHz (Typical Values at Fo = 27MHz)
Tri-State Input Voltage (Vih and Vil)	+0.9Vdd Minimum to Enable Output; +0.1Vdd Maximum to Disable Output (High Impedance); No Connect to Enable Output.
RMS Phase Jitter	1pSec Maximum (Fj = 12kHz to 20MHz)
Start Up Time	10mSec Maximum
Storage Temperature Range	-55°C to +125°C

ENVIRONWENTAL & WEC	HANICAL SPECIFICATIONS
Fine Leak Test	MIL-STD-883, Method 1014 Condition A
Gross Leak Test	MIL-STD-883, Method 1014 Condition C
Mechanical Shock	MIL-STD-202, Method 213 Condition C
Resistance to Soldering Heat	MIL-STD-202, Method 210
Resistance to Solvents	MIL-STD-202, Method 215
Solderability	MIL-STD-883, Method 2003
Temperature Cycling	MIL-STD-883, Method 1010
Vibration	MIL-STD-883, Method 2007 Condition A



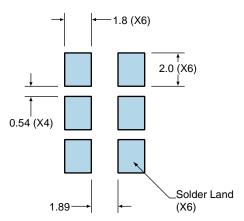
MECHANICAL DIMENSIONS (all dimensions in millimeters)



PIN	CONNECTION
1	Voltage Control
2	No Connect
3	Case Ground
4	Output
5	Tri-State
6	Supply Voltage
-	
LINE	MARKING
LINE 1	MARKING ECLIPTEK

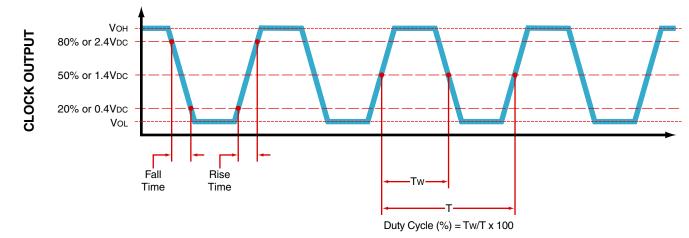
Suggested Solder Pad Layout

All Dimensions in Millimeters



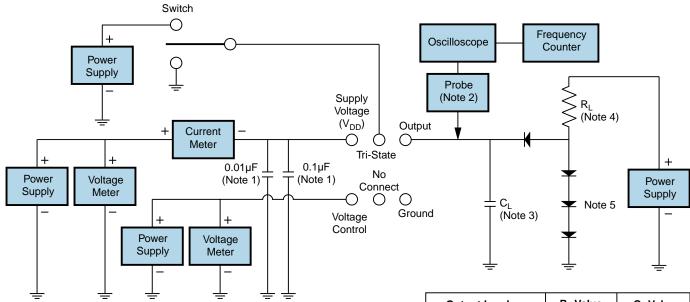
All Tolerances are ±0.1

OUTPUT WAVEFORM





Test Circuit for TTL Output



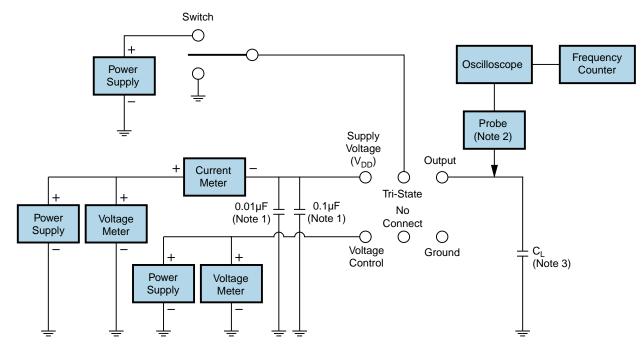
- Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance
- (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended. Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.
- Note 4: Resistance value R_L is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.
- Note 5: All diodes are MMBD7000, MMBD914, or equivalent.

Output Load R₁ Value C_L Value (Ohms) **Drive Capability** (pF) 10TTL 390 15 5TTL 780 15 2TTL 1100 6 10LSTTL 2000 15 2200 1TTL 3

Table 1: R_L Resistance Value and C_L Capacitance Value Vs. Output Load Drive Capability



Test Circuit for CMOS Output

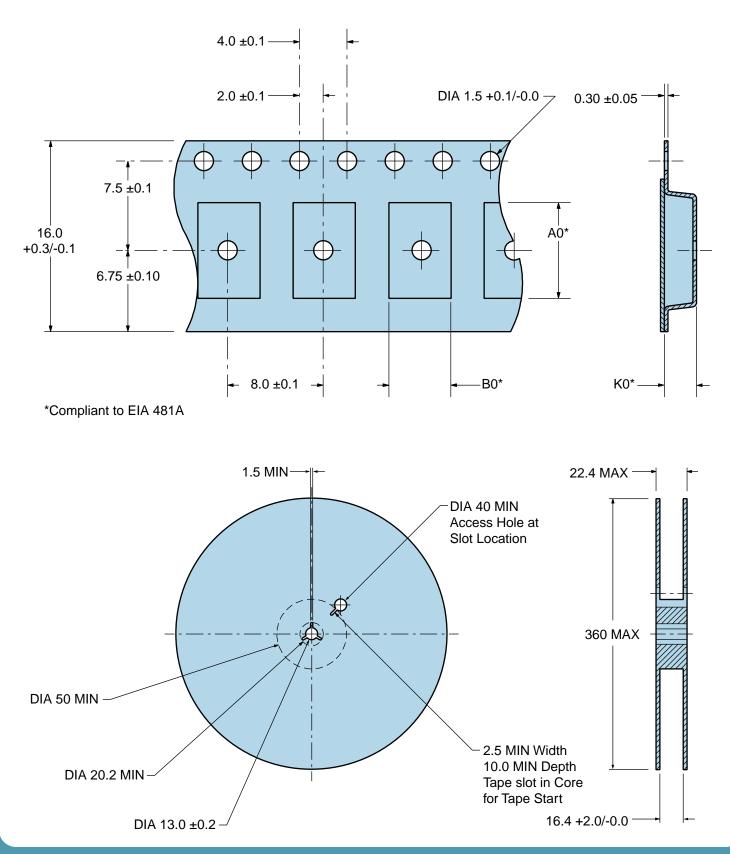


- Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.
- Note 3: Capacitance value C_{L} includes sum of all probe and fixture capacitance.



Tape & Reel Dimensions

Quantity Per Reel: 1,000 units



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Recommended Solder Reflow Methods

EV31C3A5A1-27.000M TR



High Temperature Infrared/Convection

T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	150°C
- Temperature Typical (T _s TYP)	175°C
- Temperature Maximum (T _s MAX)	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T _L to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T _L)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t _p)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1



Recommended Solder Reflow Methods

EV31C3A5A1-27.000M TR



Low Temperature Infrared/Convection 240°C

T _s MAX to T _L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	N/A
- Temperature Typical (T _s TYP)	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T⊾ to T _P)	5°C/second Maximum
Time Maintained Above:	
· Temperature (T∟)	150°C
· Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
arget Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Fime within 5°C of actual peak (t _ρ)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.